

FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. NIP-261		SERIAL NO.	
LIST OF DOCUMENTS CITED BY APPLICANT <i>(Use several sheets if necessary)</i>				APPLICANT Y. TAKEZAWA et al		GROUP	
				FILING DATE February 26, 2002			
U.S. PATENT DOCUMENTS							
*	EXAMINER INITIAL	DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	A.A.	AL 11-330185	11/30/99	Japan (w/ English Abstract)	H01L	21/66	<input type="checkbox"/> <input checked="" type="checkbox"/>
		AM 2000-131243	05/12/00	Japan (w/ English Abstract)	G01N	21/89	<input type="checkbox"/> <input checked="" type="checkbox"/>
		AN 11-235097	08/27/99	Japan (w/ English Abstract)	H02P	9/00	<input type="checkbox"/> <input checked="" type="checkbox"/>
		AO 9-222393	08/26/97	Japan (w/ English Abstract)	G01N	21/27	<input type="checkbox"/> <input checked="" type="checkbox"/>
	↓	AP 10-115601	05/06/98	Japan (w/ English Abstract)	G01N	29/00	<input type="checkbox"/> <input checked="" type="checkbox"/>
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
	↓	AR	T. Ikeda et al, "Development of the Ultrasonic Degradation Tester for Low Voltage Cables", TRANSACTIONS OF THE INSTITUTE OF ELECTRICAL ENGINEERS OF JAPAN, Vol. 120-B, No. 11, pp. 1437-1442, 2000.				
		AS					
		AT					
EXAMINER				DATE CONSIDERED			
Amir ALAVI				12-1-2004			

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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#		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL	11-118773	04/30/99	Japan (w/ English Abstract)	G01N	29/10	<input type="checkbox"/>	<input checked="" type="checkbox"/>
	AM	10-19856	01/23/98	Japan (w/ English Abstract)	G01N	29/18	<input type="checkbox"/>	<input checked="" type="checkbox"/>
	AN	7-35732	02/07/95	Japan (w/ English Abstract)	G01N	29/18	<input type="checkbox"/>	<input checked="" type="checkbox"/>
✓	AO	7-245869	09/19/95	Japan (w/ English Abstract)	H02H	5/10	<input type="checkbox"/>	<input checked="" type="checkbox"/>
	AP						<input type="checkbox"/>	<input type="checkbox"/>

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

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